



Product Name	Slim Star 620 Laser, Slim Star 720 Laser
Model No.	GK-070015, GK-070016
FCC ID.	FSUGKZH7

Applicant	KYE SYSTEMS CORP. (Genius)
Address	No.492 Sec.5, Chung Hsin Rd., San Chung,
	Taipei Hsien, 24160, Taiwan, R.O.C.

Date of Receipt	Feb. 21 2008
Issued Date	Mar. 19, 2008
Report No.	082245R-RFUSP03V01
Version	V1.0

The Test Results relate only to the samples tested.

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Test Report Certification

Test Date: Mar. 19, 2008

Report No.: 082245R-RFUSP03V01



Product Name	Slim Star 620 Laser, Slim Star 720 Laser			
Applicant	KYE SYSTEMS CORP. (Genius)			
Address	No.492 Sec.5, Chung Hsin Rd., San Chung, Taipei Hsien,			
	24160, Taiwan, R.O.C.			
Manufacturer	KYE SYSTEMS CORP. (Genius)			
Model No.	GK-070015, GK-070016			
FCC ID.	FSUGKZH7			
Rated Voltage	AC 120V/60Hz			
EUT Working Voltage	DC 3V(Power By Battery)			
Trade Name	Genius			
Applicable Standard	FCC CFR Title 47 Part 15 Subpart C: 2007			
	ANSI C63.4: 2003			
	CISPR 22: 2005	NVLAP Lab Code: 200533-0		
Test Result	Complied			

The Test Results relate only to the samples tested.

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Documented By :

Approved By

(Adm. Specialist / Genie Chang)

Genie Chang

Tested By : Molin huang

(Engineer / Molin Huang)

(Deputy Manager / Vincent Lin)

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FC

Testing Laboratory

0914



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Attachment 1: EUT Test Photographs Attachment 2: EUT Detailed Photographs



1. GENERAL INFORMATION

1.1. EUT Description

Product Name	Slim Star 620 Laser, Slim Star 720 Laser
Trade Name	Genius
Trade Name	Octilus
FCC ID.	FSUGKZH7
Model No.	GK-070015, GK-070016
EUT Working Voltage	DC 3V(Power By Battery)
Frequency Range	27.145MHz
Type of Modulation	FSK Modulation
Type of antenna	Soldered on PCB
Number of Channel	1
Channel Control	Manual

Frequency of Each Channel:

Channel O1: Frequency 27.145MHz

Note:

- 1. The EUT is a Slim Star 620 Laser, Slim Star 720 Laser used in household and office PC system or related application.
- 2. The EUT is including two models and the difference is counted differently for the button.
- 3. These tests were conducted on a sample of the equipment for the purpose of demonstrating compliance with FCC CFR Title 47 Part 15 Subpart C Paragraph 15.227.



1.2. Operational Description

The EUT is a Slim Star 620 Laser, Slim Star 720 Laser used in household and office PC system. The number of the channels is 1 in 27.145MHz.

The device adapts FSK modulation. The Printed antenna provides diversity function to improve the transmitting function.

Test Mode	Mode 1: Transmitter
-----------	---------------------



1.3. Test System Details

The types for all equipment, plus descriptions of all cables used in the tested system (including inserted cards) are:

Product	Manufacturer	Model No.	Serial No.	FCC ID	Power Cord
N/A					
					_
Signal Cable Type Signal cable Description					

N/A

1.4. Configuration of Test System

EUT	

1.5. EUT Exercise Software

1	Setup the EUT as shown on 1.4.
2	Turn on the power for EUT.
3	The EUT to enter RF test mode.
4	The EUT will continuously transmit the radio signal.
5	Repeat the above procedure (3) to (4)



1.6. Test Facility

Ambient conditions in the laboratory:

Items	Required (IEC 68-1)	Actual
Temperature (°C)	15-35	20-35
Humidity (%RH)	25-75	30-65
Barometric pressure (mbar)	860-1060	950-1000

Site Description: Federal Communications Commission

FCC Engineering Laboratory 7435 Oakland Mills Road Columbia, MD 21046

Registration Number: 92195

Accreditation on NVLAP NVLAP Lab Code: 200533-0

Site Name: Quietek Corporation

Site Address: No. 5-22, Ruei-Shu Valley, Ruei-Ping Tsuen,

Lin-Kou Shiang, Taipei,

Taiwan, R.O.C.

TEL: 886-2-8601-3788 / FAX: 886-2-8601-3789

E-Mail: service@quietek.com

FCC Accreditation Number: TW1014







2. Conducted Emission

2.1. Test Equipment

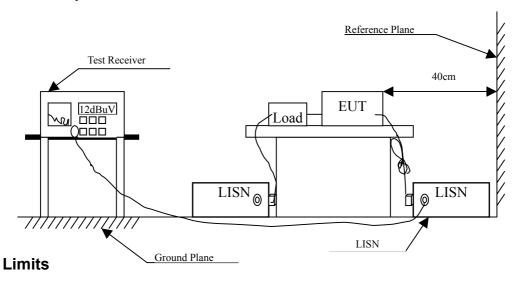
The following test equipments are used during the conducted emission test:

Item	Instrument	Manufacturer	Type No./Serial No	Last Cal.	Remark
1	Test Receiver	R&S	ESCS 30/838251/001	May, 2007	
2	L.I.S.N.	R&S	ESH3-Z5/836679/0023	May, 2007	EUT
3	L.I.S.N.	R&S	ENV 4200/833209/0023	May, 2007	Peripherals
4	Pulse Limiter	R&S	ESH3-Z2	May, 2007	
6	No.1 Shielded Room				

Note: 1. All equipments are calibrated with traceable calibrations. Each calibration is traceable to the national or international standards.

2.2. Test Setup

2.3.



FCC Part 15 Subpart C Paragraph 15.207 (dBuV) Limit					
Frequency	Limits				
MHz	QP	AV			
0.15 - 0.50	66-56	56-46			
0.50-5.0	56	46			
5.0 - 30	60	50			

Remarks: In the above table, the tighter limit applies at the band edges.



2.4. Test Procedure

The EUT was setup and tested according to ANSI C63.4, 2003 test procedure.

The EUT was placed on a platform of nominal size, 1 m by 1.5 m, raised 80 cm above the conducting ground plane. The vertical conducting plane was located 40 cm to the rear of the EUT. All other surfaces of EUT were at least 80 cm from any other grounded conducting surface. The EUT and simulators are connected to the main power through a line impedance stabilization network (LISN). The LISN provides a 50 ohm /50uH coupling impedance for the measuring equipment. The peripheral devices are also connected to the main power through a LISN. (Please refer to the block diagram of the test setup and photographs.)

Each current-carrying conductor of the EUT power cord, except the ground (safety) conductor, was individually connected through a LISN to the input power source. The excess length of the power cord between the EUT and the LISN receptacle were folded back and forth at the center of the lead to form a bundle not exceeding 40 cm in length.

Conducted emissions were investigated over the frequency range from 0.15MHz to 30MHz using a receiver bandwidth of 9kHz.

2.5. Uncertainty

 \pm 2.26 dB

2.6. Test Data of Conducted Emission

The EUT is powered by batteries Owing to the DC operation. This test item is not performed



3. Radiated Emission

3.1. Test Equipment

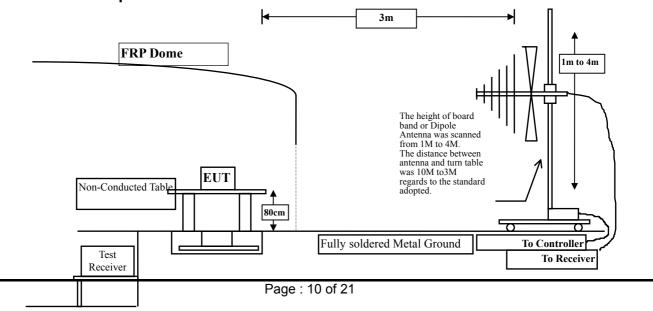
The following test equipment are used during the radiated emission test:

Test Site	Equipment	Manufacturer	Model No./Serial No.	Last Cal.
☐Site # 1	Test Receiver	R&S	ESVS 10 / 834468/003	May, 2007
	Spectrum Analyzer	Advantest	R3162/ 00803480	May, 2007
	Pre-Amplifier	Advantest	BB525C/ 3307A01812	May, 2007
	Bilog Antenna	SCHAFFNER	CBL6112B / 2697	Sep., 2007
☐Site # 2	Test Receiver	R&S	ESCS 30 / 836858 / 022	May, 2007
	Spectrum Analyzer	Advantest	R3162 / 100803466	May, 2007
	Pre-Amplifier	Advantest	BB525C/3307A01814	May, 2007
	Bilog Antenna	SCHAFFNER	CBL6112B / 2705	May, 2007
	Horn Antenna	ETS	3115 / 0005-6160	Sep., 2007
	Pre-Amplifier	QTK	QTK-AMP-01/ 0001	May, 2007
⊠Site # 3	Test Receiver	R&S	ESI 26 / 838786/004	May, 2007
	Spectrum Analyzer	Agilent	E4407B / US39440758	May, 2007
	Bilog Antenna	SCHAFFNER	CBL6112B / 2697	May, 2007
	Horn Antenna	Schwarzbeck	BBHA9120D / 305, 306	July, 2007
	Horn Antenna	Schwarzbeck	BBHA9170 / 208, 209	July, 2007
	Pre-Amplifier	QTK	QTK-AMP-01 / 0001	July, 2007
	Pre-Amplifier	QTK	QTK-AMP-03 / 0003	May, 2007
	Pre-Amplifier	HP	8449B / 3008A01123	July, 2007

Note: 1. All equipments are calibrated with traceable calibrations. Each calibration is traceable to the national or international standards.

2. The test instruments marked with "X" are used to measure the final test results.

3.2. Test Setup





3.3. Limits

> FCC Part 15 Subpart C Paragraph 15.227 Limit

FCC Part 15 Subpart C Paragraph 15.227 Limits					
Fundamental Frequency MHz	Field strength of fundamental				
	uV/m	dBuV/m			
26.96-27.28	10000	80			

Remarks:

- 1. E field strength $(dBuV/m) = 20 \log E$ field strength (uV/m)
- > Frequencies in restricted band are complied to limits on Paragraph 15.209.

FCC Part 15 Subpart C Paragraph 15.209 Limits					
Frequency MHz uV/m @3m dBuV/m@3m					
30-88	100	40			
88-216	150	43.5			
216-960	200	46			
Above 960	500	54			

Remarks : 1. E field strength (dBuV/m) = 20 log E field strength (uV/m)

2. In the Above Table, the tighter limit applies at the band edges.



3.4. Test Procedure

The EUT was setup and tested according to ANSI C63.4, 2003.

The EUT is placed on a turn table which is 0.8 meter above ground. The turn table is rotated 360 degrees to determine the position of the maximum emission level. The EUT was positioned such that the distance from antenna to the EUT was 3 meters.

The antenna is scanned from 1 meter to 4 meters to find out the maximum emission level. This is repeated for both horizontal and vertical polarization of the antenna. In order to find the maximum emission, all of the interface cables were manipulated according to ANSI C63.4:2003 on radiated measurement.

The resolution bandwidth below 1GHz setting on the field strength meter is 120 kHz and above 1GHz is 1MHz.

The frequency range from 30MHz to 10th harminics is checked.

3.5. Uncertainty

- ± 3.9 dB above 1GHz
- + 3.8 dB below 1GHz



3.6. Test Data of Radiated Emission

Product : Slim Star 620 Laser, Slim Star 720 Laser

Test Item : Fundamental Radiated Emission

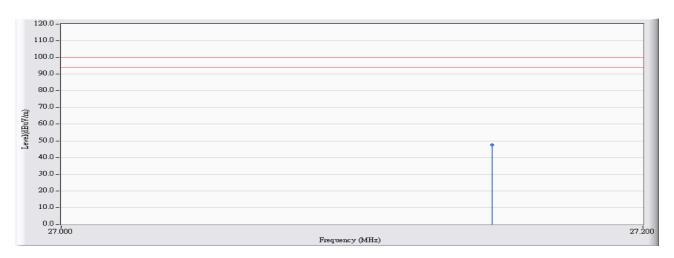
Test Site : No.3 OATS
Test Voltage : AC 120V/60Hz

Test Mode : Mode 1: Transmitter

Polarity	Frequency	Correct	Reading Level	Measure Level	Margin	Peak Limit	Average Limit
	(MHz)	Factor	(dBuV)	(dBuV/m)	(dB)	(dBuV/m)	(dBuV/m)
		(dB)					
Peak Detector							
X	27.148	-3.490	50.970	47.480	-52.520	100.000	80.000
Υ	27.148	-3.490	58.890	55.400	-44.600	100.000	80.000
Z	27.148	-3.490	58.630	55.140	-44.860	100.000	80.000

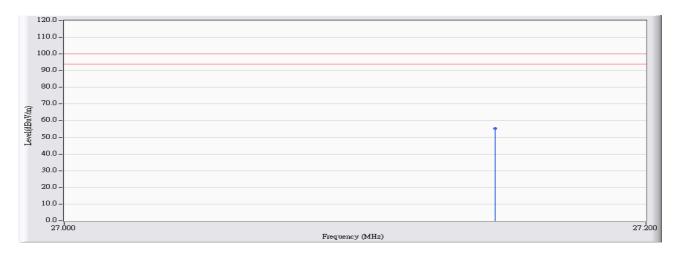
Peak Detector:

Polarity X

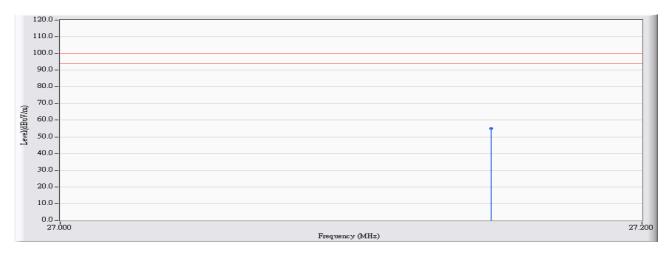




Polarity Y



Polarity Z



Note:

- 1. Below 30MHz, the magnetic loop antenna was used.
- 2. Only fundamental frequency is shown on the test report.
- 3. For those measured radiated emissions below 30MHz not shown above, mean they are below the limit.
- 4. Correct factor = Antenna Factor + Cable Loss Pre-amplifier Gain



Product : Slim Star 620 Laser, Slim Star 720 Laser

Test Item : General Radiated Emission

Test Site : No.3 OATS
Test Voltage : AC 120V/60Hz
Test Mode : Mode 1: Transmitter

Frequency	Correct	Reading	Measurement	Margin	Limit
. ,	Factor	Level	Level	J	
MHz	dB	dBuV	dBuV/m	dB	dBuV/m
Horizontal					
134.650	11.813	12.655	24.467	-19.033	43.500
189.920	9.539	16.478	26.018	-17.482	43.500
256.850	14.129	12.030	26.159	-19.841	46.000
311.520	14.026	11.250	25.276	-20.724	46.000
379.500	16.631	13.455	30.086	-15.914	46.000
402.560	18.409	6.656	25.065	-20.935	46.000
Vertical					
133.450	12.657	13.210	25.868	-17.632	43.500
189.650	9.385	14.250	23.635	-19.865	43.500
264.850	14.104	11.220	25.325	-20.675	46.000
325.110	13.942	13.456	27.398	-18.602	46.000
366.520	15.791	11.522	27.312	-18.688	46.000
439.850	17.558	12.633	30.191	-15.809	46.000

Note:

- 1. All Readings below 1GHz are Quasi-Peak, above are performed with peak and/or average measurements as necessary.
- 2. "means the worst emission level.
- 3. Measurement Level = Reading Level + Correct Factor
- 4. Correct Factor = Antenna Factor + Cable Loss Pre-amplifier Gain



4. Band Edge

4.1. Test Equipment

The following test equipment are used during the radiated emission test:

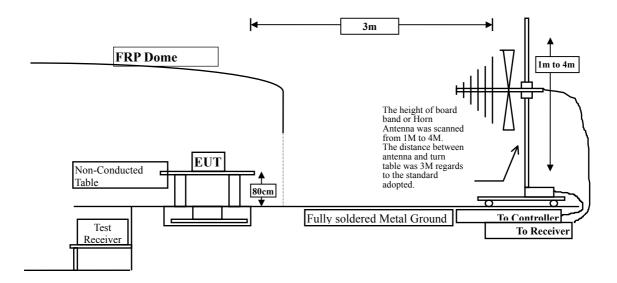
Test Site	Equipment	Manufacturer	Model No./Serial No.	Last Cal.
☐Site # 1	Test Receiver	R&S	ESVS 10 / 834468/003	July, 2007
	Spectrum Analyzer	Advantest	R3162/ 00803480	May, 2007
	Pre-Amplifier	Advantest	BB525C/ 3307A01812	May, 2007
	Bilog Antenna	SCHAFFNER	CBL6112B / 2697	Nov., 2007
☐Site # 2	Test Receiver	R&S	ESCS 30 / 836858 / 022	Nov., 2007
	Spectrum Analyzer	Advantest	R3162 / 100803466	May, 2007
	Pre-Amplifier	Advantest	BB525C/3307A01814	May, 2007
	Bilog Antenna	SCHAFFNER	CBL6112B / 2705	Oct., 2007
⊠Site # 3	Test Receiver	R&S	ESI 26 / 838786 / 004	May, 2007
	Spectrum Analyzer	HP	E4407B / US39440758	May, 2007
	Pre-Amplifier	QTK	QTK-AMP-03 / 0003	May, 2007
	Broadband Antenna	Schwarzbeck	VULB9166/1085	April, 2007
	Horn Antenna	ETS	3115 / 0005-6160	July, 2007
	Loop Antenna	R&S	HFH2-Z2/833799/004	July, 2007
	Pre-Amplifier	QTK	QTK-AMP-01 / 0001	July, 2007

Note:

- 1. All equipments are calibrated every one year.
- 2. The test instruments marked by "X" are used to measure the final test results.

4.2. Test Setup

RF Radiated Measurement:



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4.3. Limit

Attenuation below the general limits specified in Section 15.209(a) is not required. In addition, radiated emissions which fall in the restricted bands, as defined in Section 15.205(a), must also comply with the radiated emission limits specified in Section 15.209(a) (see Section 15.205(c)).

4.4. Test Procedure

The EUT was setup and tested according to ANSI C63.4, 2003.

The EUT is placed on a turn table which is 0.8 meter above ground. The turn table is rotated 360 degrees to determine the position of the maximum emission level. The EUT was positioned such that the distance from antenna to the EUT was 3 meters.

The antenna is scanned from 1 meter to 4 meters to find out the maximum emission level. This is repeated for both horizontal and vertical polarization of the antenna. In order to find the maximum emission, all of the interface cables were manipulated according to ANSI C63.4:2003 on radiated measurement.

The additional latch filter below 1GHz was used to measure the level of harmonics radiated emission during field dtrength of harmonics measurement.

The bandwidth below 30MHz setting on the field strength meter is 9 kHz



4.5. Test Result of Band Edge

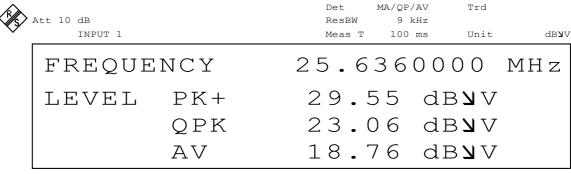
Product : Slim Star 620 Laser, Slim Star 720 Laser

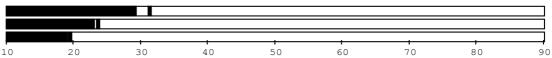
Test Item : Band Edge Test Site : No.3 OATS

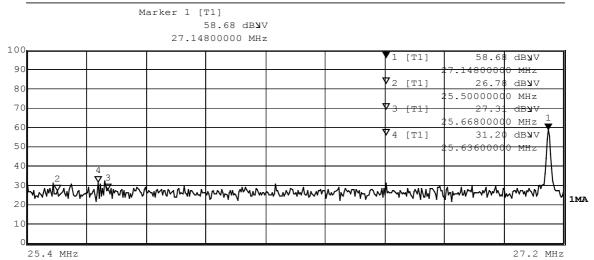
Test Mode : Mode 1: Transmitter

RF Radiated Measurement: (Peak Detector)

Frequency	Correct Factor	Reading Level	Measure Level	Margin (dB)	Limit
(MHz)	(dB)	(dBuV)	(dBuV/m)		(dBuV/m)
25.636	-3.450	29.550	26.100	-12.980	39.08







Date: 10.MAR.2008 21:04:41



5. EMI Reduction Method During Compliance Testing

No modification was made during testing.

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Attachment 1: EUT Test Photographs

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Attachment 2: EUT Detailed Photographs

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